



This work is sponsored by the
Air Force Research Laboratory (AFRL/RVSE)
TPOC: Mr. Keith Avery

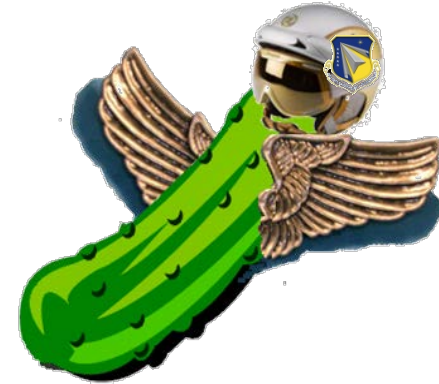
A SPA-1 ASIC Operating at 0.5V Fabricated in 130nm Double Gated CMOS

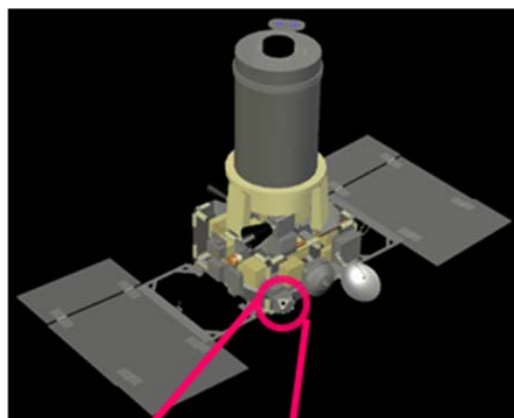
24 August 2011



Goal – Ultra Low Power ASIMs for Satellite Plug-N-Play

- Phase 1 SBIR - Feasibility Demonstration
 - Ultra low power PIC (picL) microprocessor core
 - Performance capable of meeting ASIM needs
 - Radiation tolerant for space applications
 - Proved feasibility of Double Gate Flexfet technology for ASIC development
- Phase 2 SBIR – Build Prototypes of SPA-1 Mini-PnP ASIC
- Phase 3 SBIR – Technical Qualifications, Flight Testing, and other ASIM Derivatives (SPA-U, SPA-S, ...)

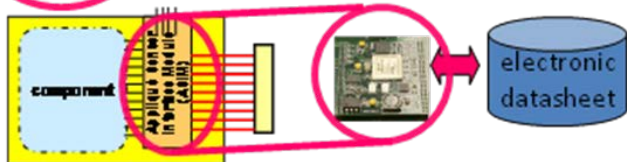




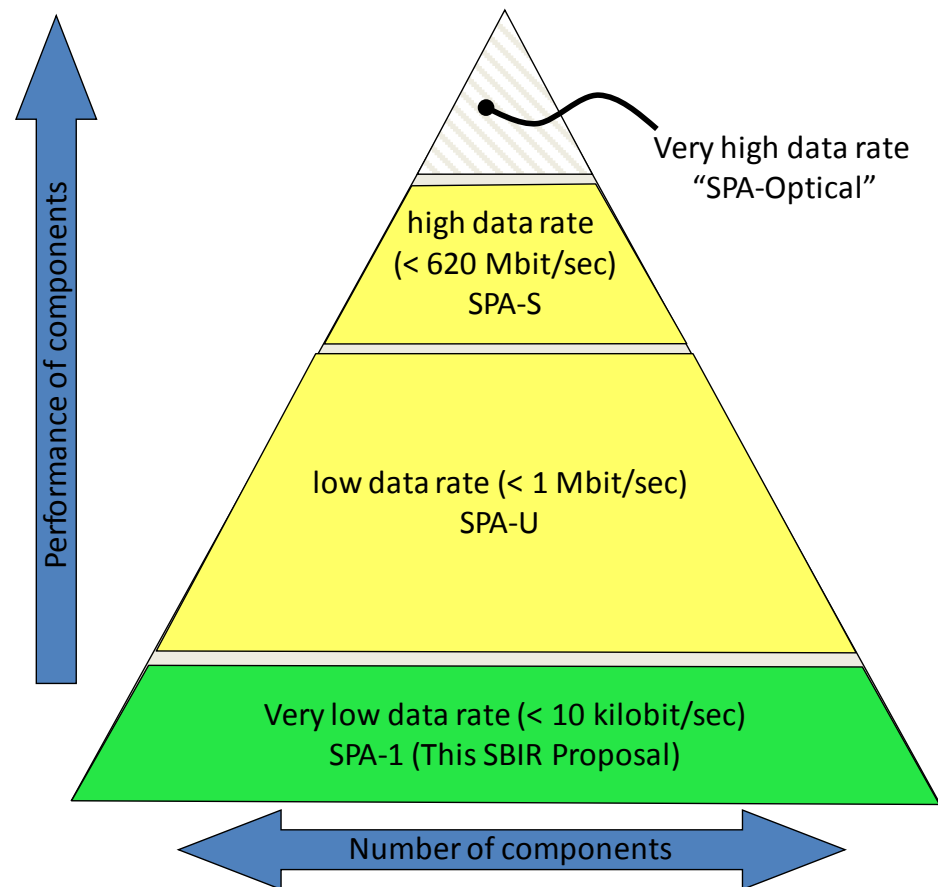
SPA Satellite

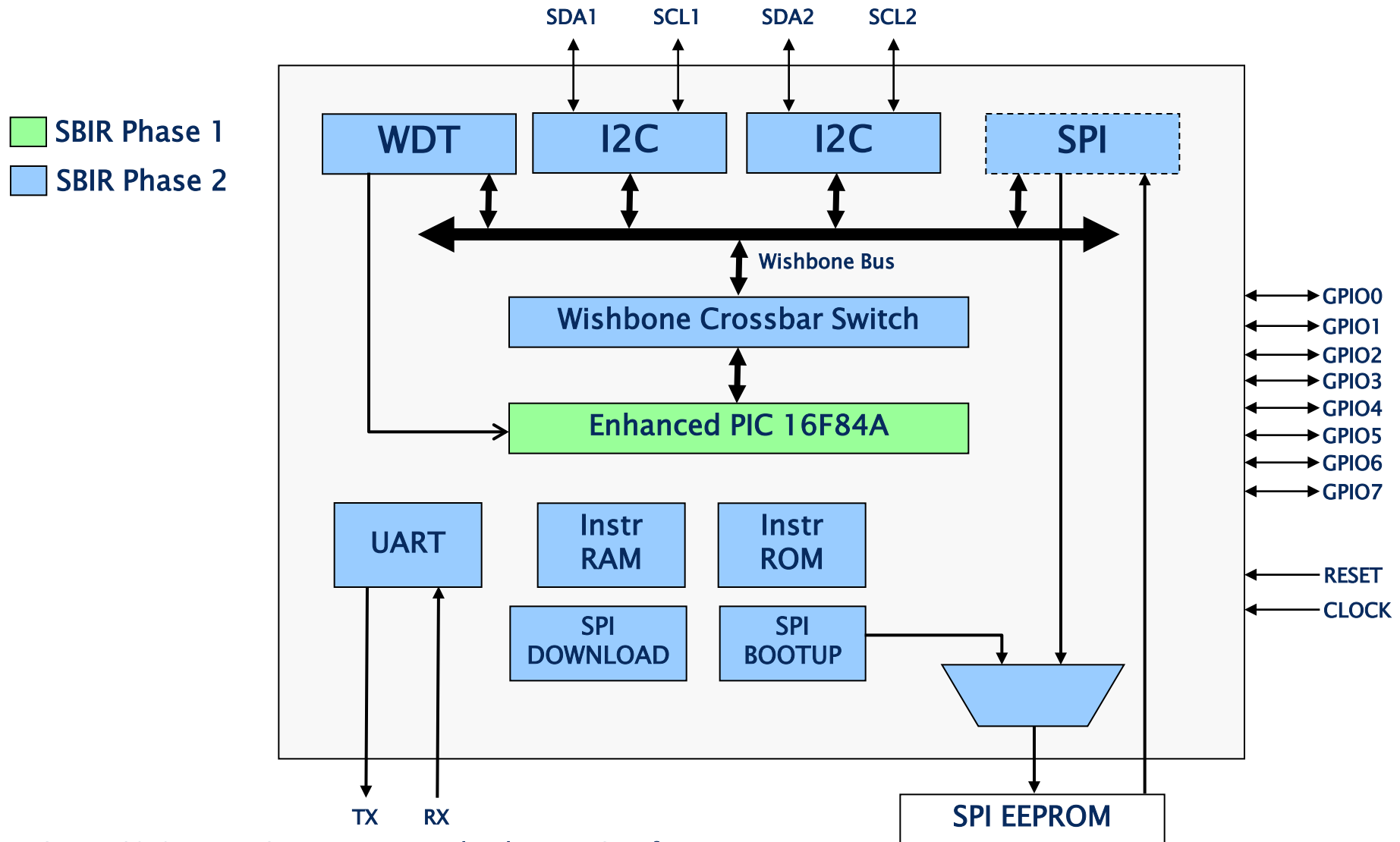


SPA plug-and-play
component



SPA interface module

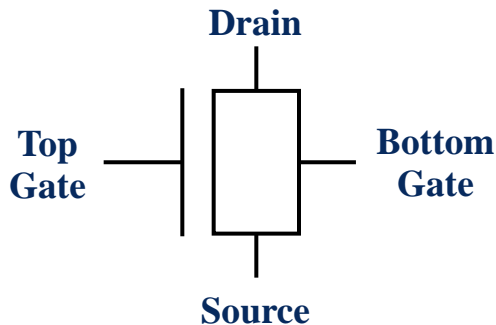




Source: 2010 AFRL/RVSE Mini-PnP External Architecture Specification

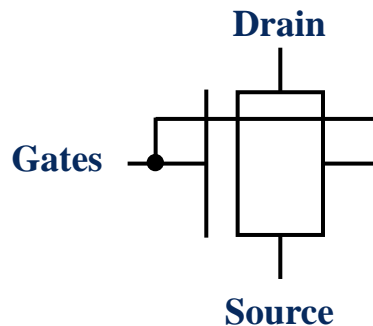
Flexfet features

- MIGFET (Multiple Independent Gate FET)
- MUGFET (Multiple Gate FET)
- Fully depleted SOI MOSFET Top Gate
- Self-aligned JFET Bottom Gate



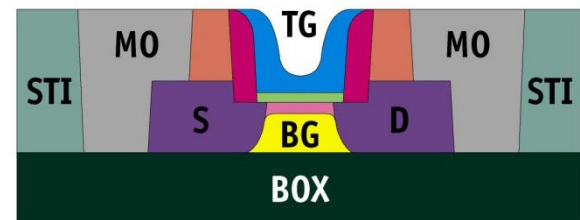
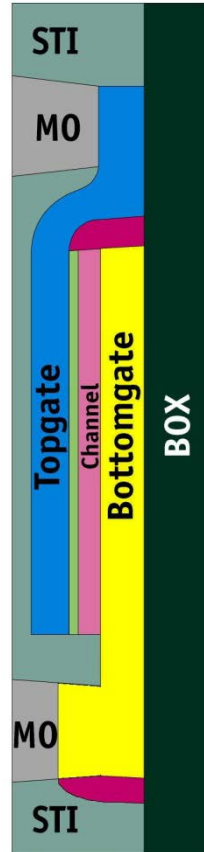
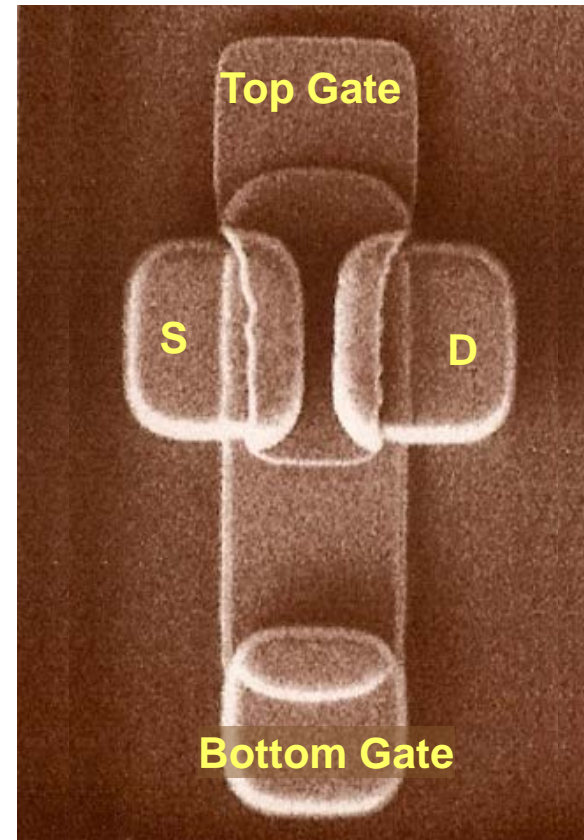
MIGFET

Benefit
Dynamic Threshold Control

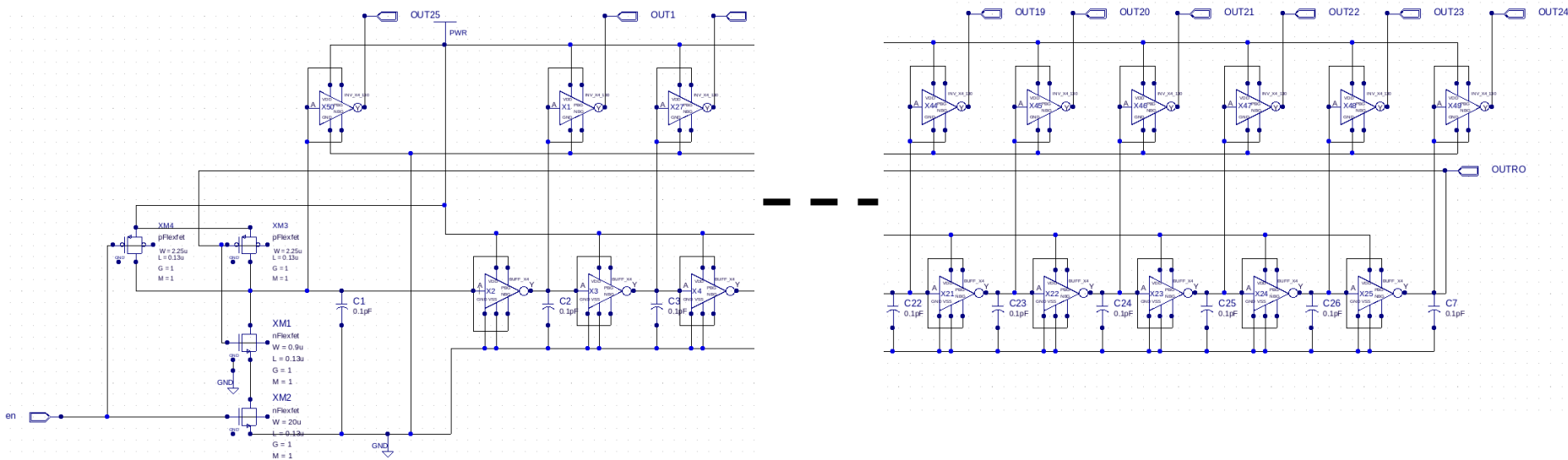


MUGFET

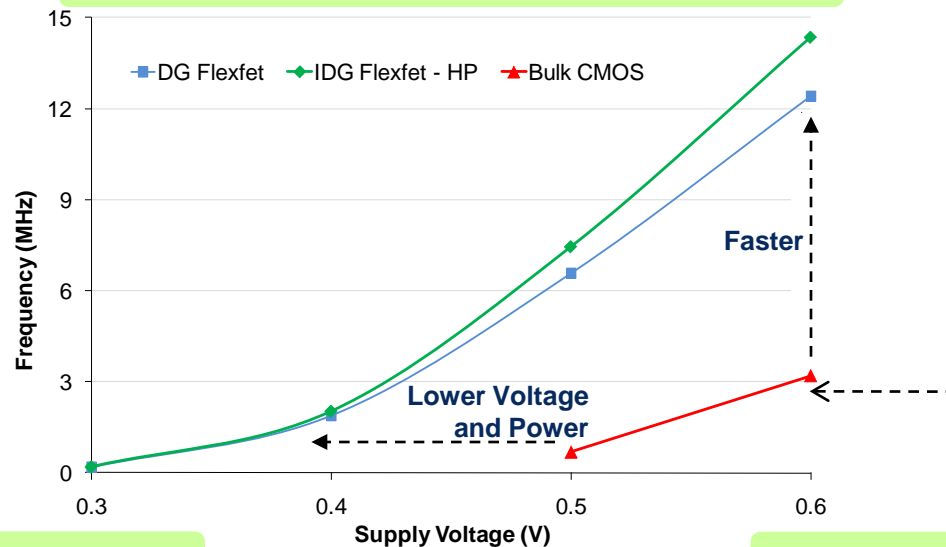
Benefit
Ultra Low Power



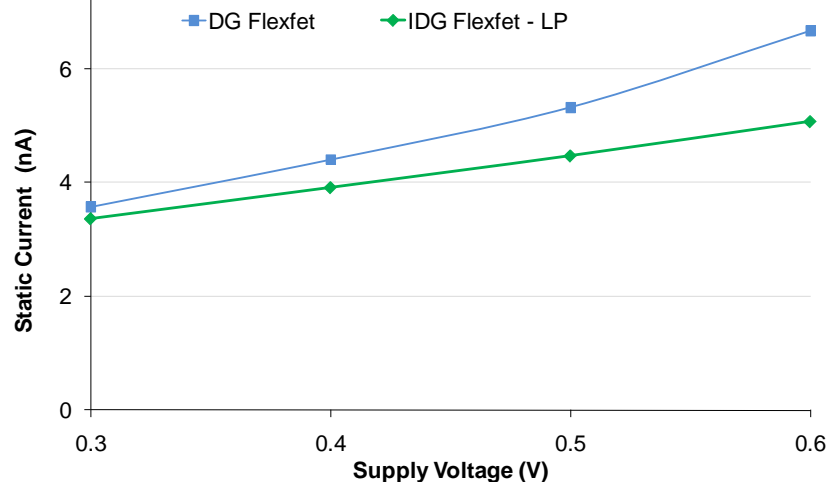
- Ring oscillator performance comparison
 - 130nm Flexfet IDG, DG, and high volume commercial bulk CMOS
 - 25 inverters with loading of 4x inverter load plus wiring capacitance



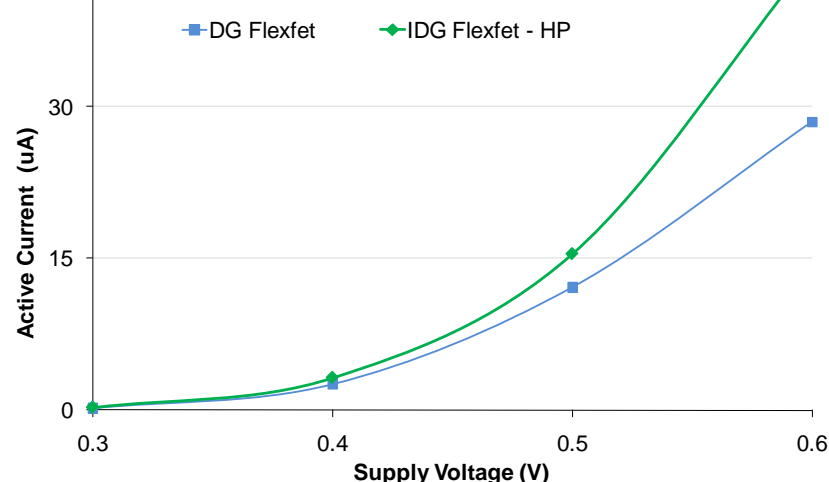
Frequency – IDG and DG versus Bulk CMOS

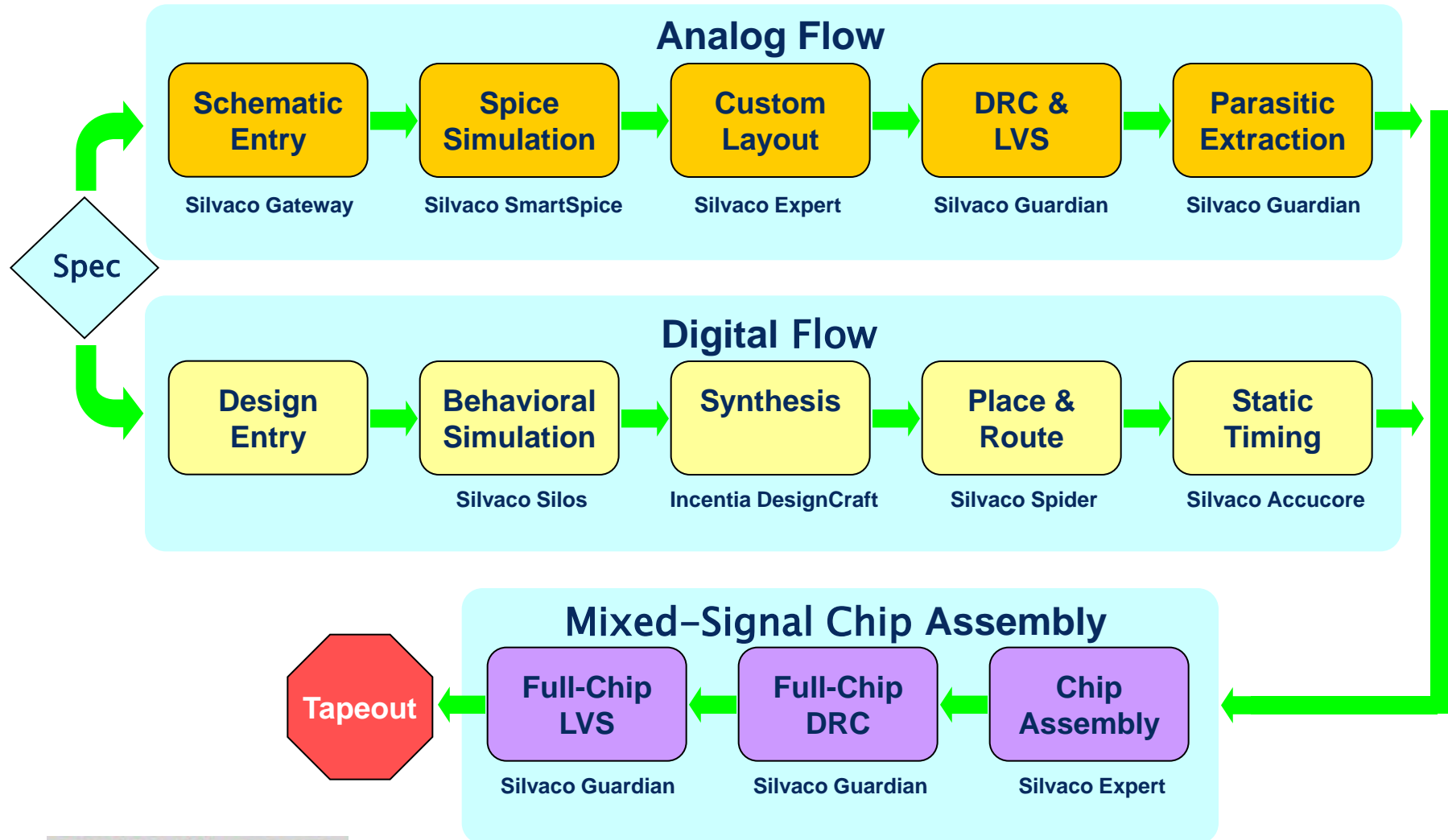


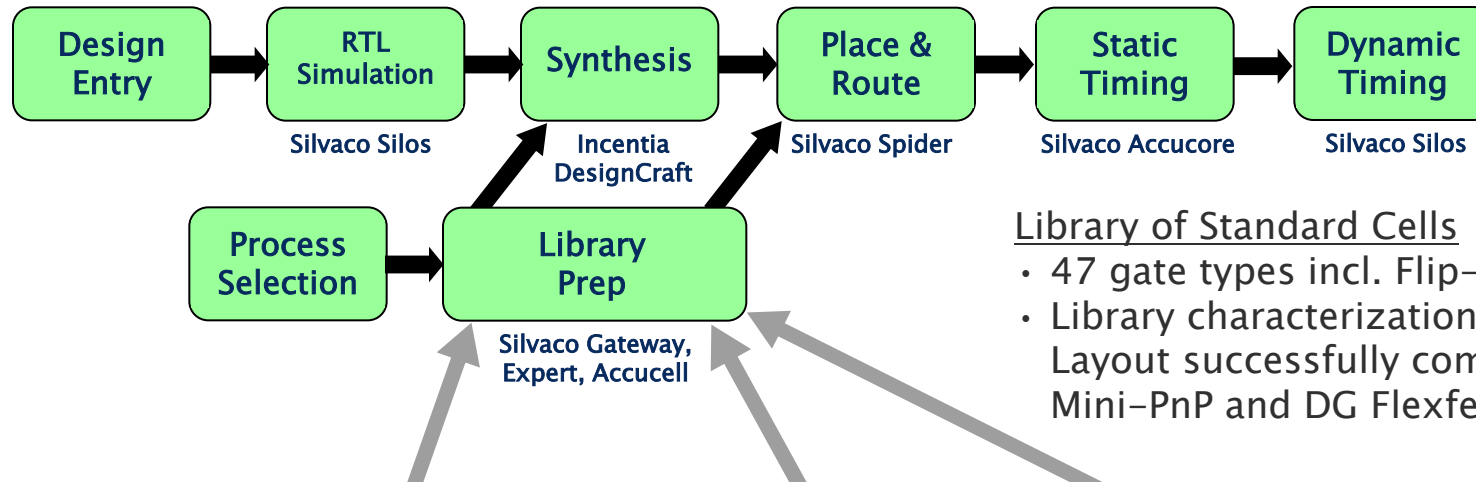
Static Current: IDG vs. DG



Active Current: IDG vs. DG

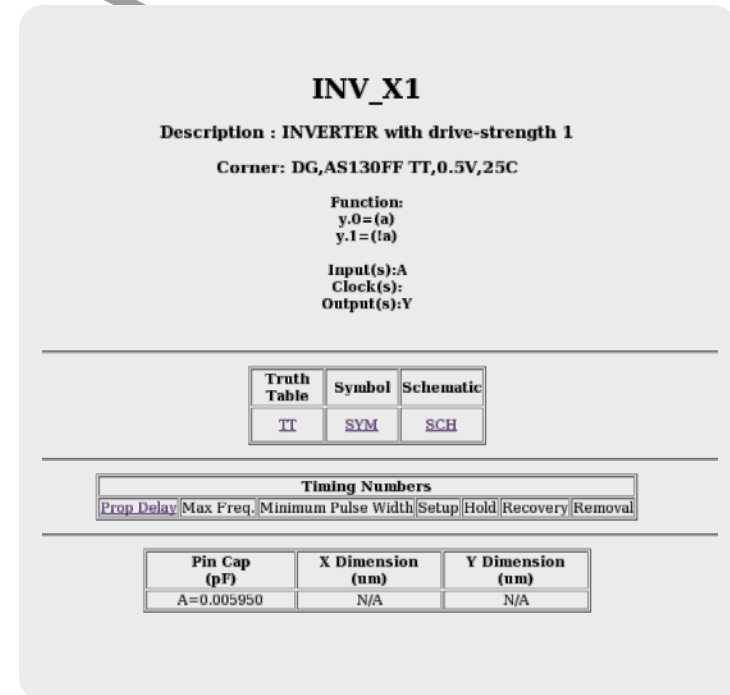
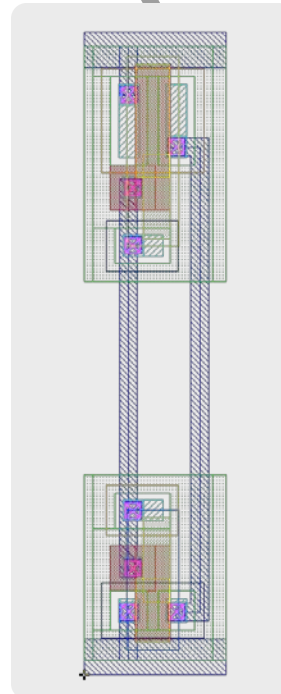
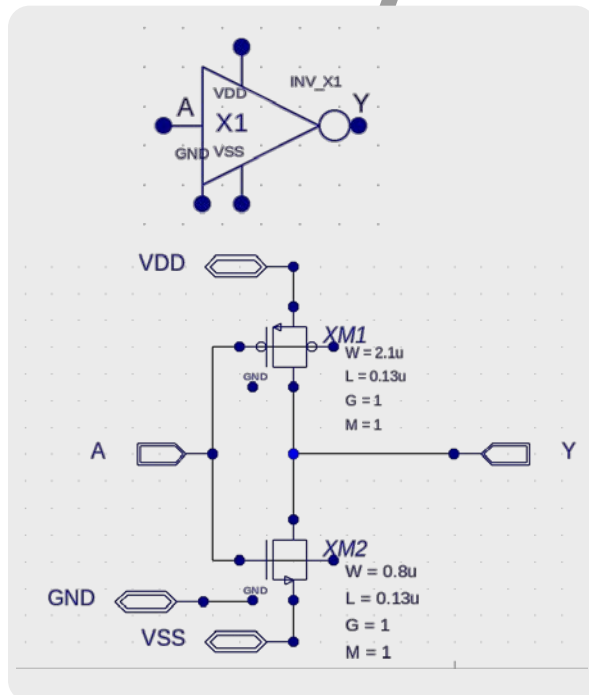






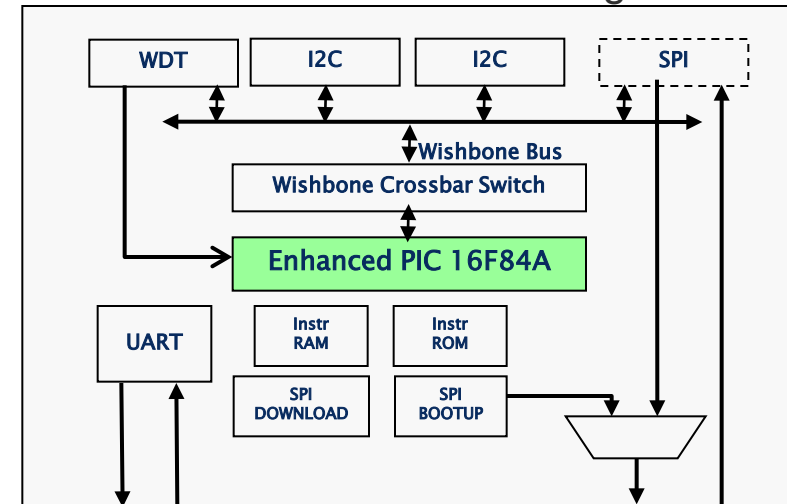
Library of Standard Cells

- 47 gate types incl. Flip-Flops and Latch
- Library characterization, Synthesis and Layout successfully completed for picL, Mini-PnP and DG Flexfet Test Chip





AFRL Mini-PnP Block Diagram



picL ULP Core

- PIC 16F84A Core
- 50MHz Synthesis at 0.5V
- Clock tree inserted
- 2063 components
- 2420 signal nets, 1clock net
- 3 layer metal with local interconnect

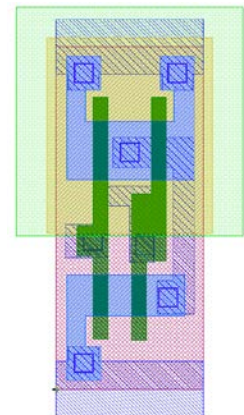
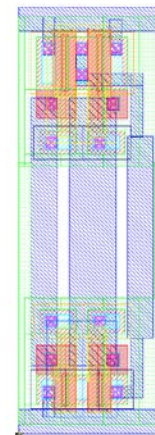
50MHz synthesis	Flexfet 0.5V, 130nm	Bulk CMOS 1.5V, 130nm	Unit
Cells used	2063	1610	#
Total Cell Input switching power	0.43	1.41	mW
Leakage Power	61.9	45.2	nW
Average Leakage power per cell	30.2	28.1	pW

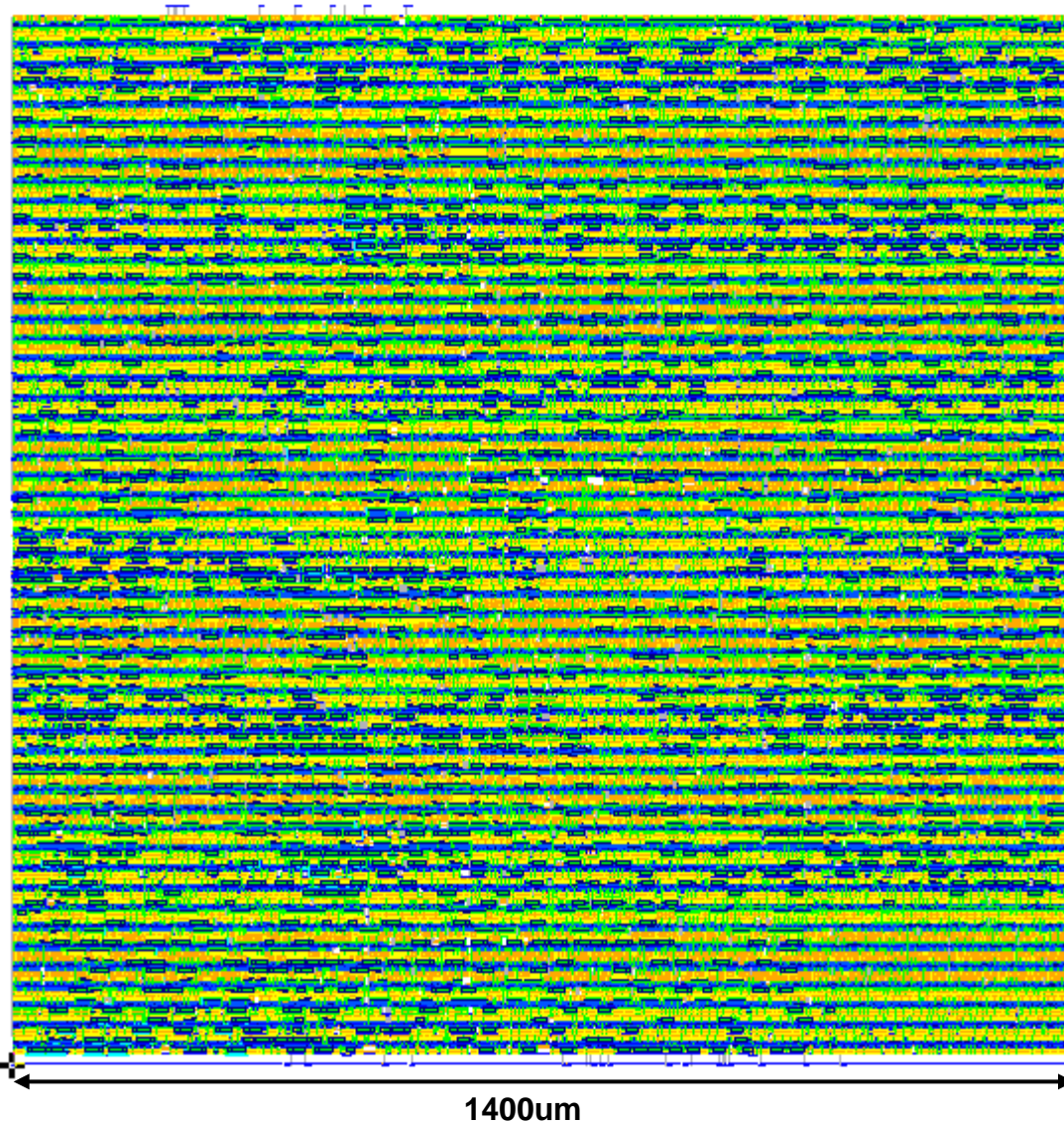
- No area penalty for Flexfet's second gate

Std Cell Example	Flexfet 130nm (um ²)	Bulk CMOS 130nm (um ²)
NAND2, NOR2	58.3	53.7
D-type Flip-Flop	279.9	348.5
Inverter x1	46.7	40.3
Total picL cell area	183,246	183,986

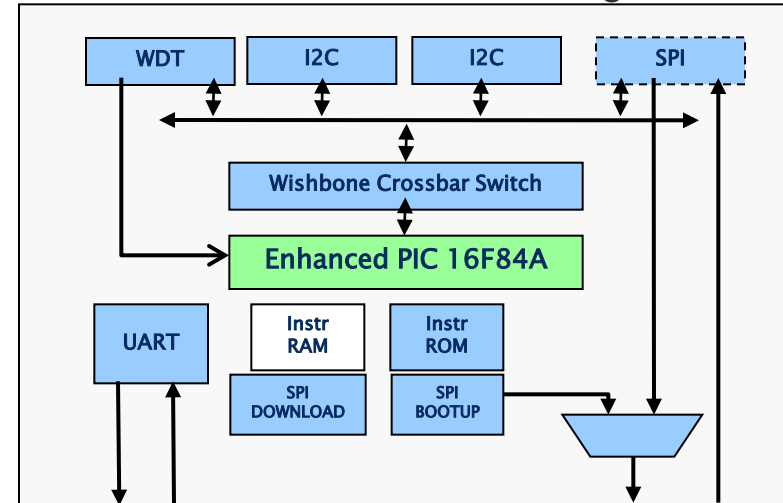
NAND Gates

DG Flexfet 130nm Bulk CMOS 130nm
 4.5um X 12.96um 4.9um X 12.1um





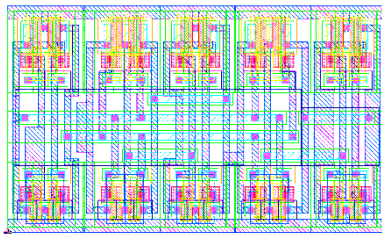
AFRL Mini-PnP Block Diagram



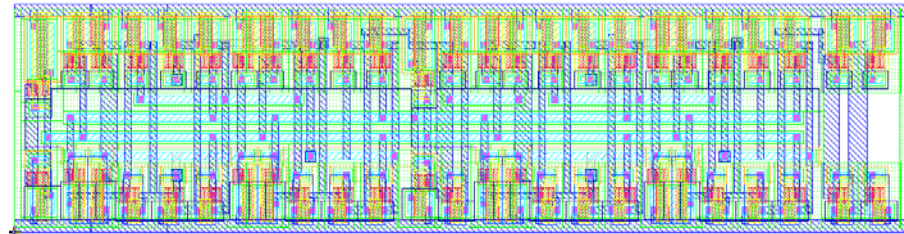
Top Level Mini-PnP

- Synthesized ROM
- Required Latches, Set and Reset FFs, and Tri-State buffers
- 50MHz synthesis at 0.5V
- Clock tree inserted
- 14504 Components
- 14987 Signals, 1 clock net
- 3 Layer metal

- SEL: Flexfet is an SOI process (inherently immune to latch-up)
- TID: Flexfet bottom gate is designed to minimize the effect of charge trapped in the BOX
- SET: Cell library design - Rising and falling logic delays were balanced to minimize pulse spreading associated with Single Event Transients
- SEU: Mitigation per AFRL recommendations
 - Added DICE Flip-Flops to DG standard cell library

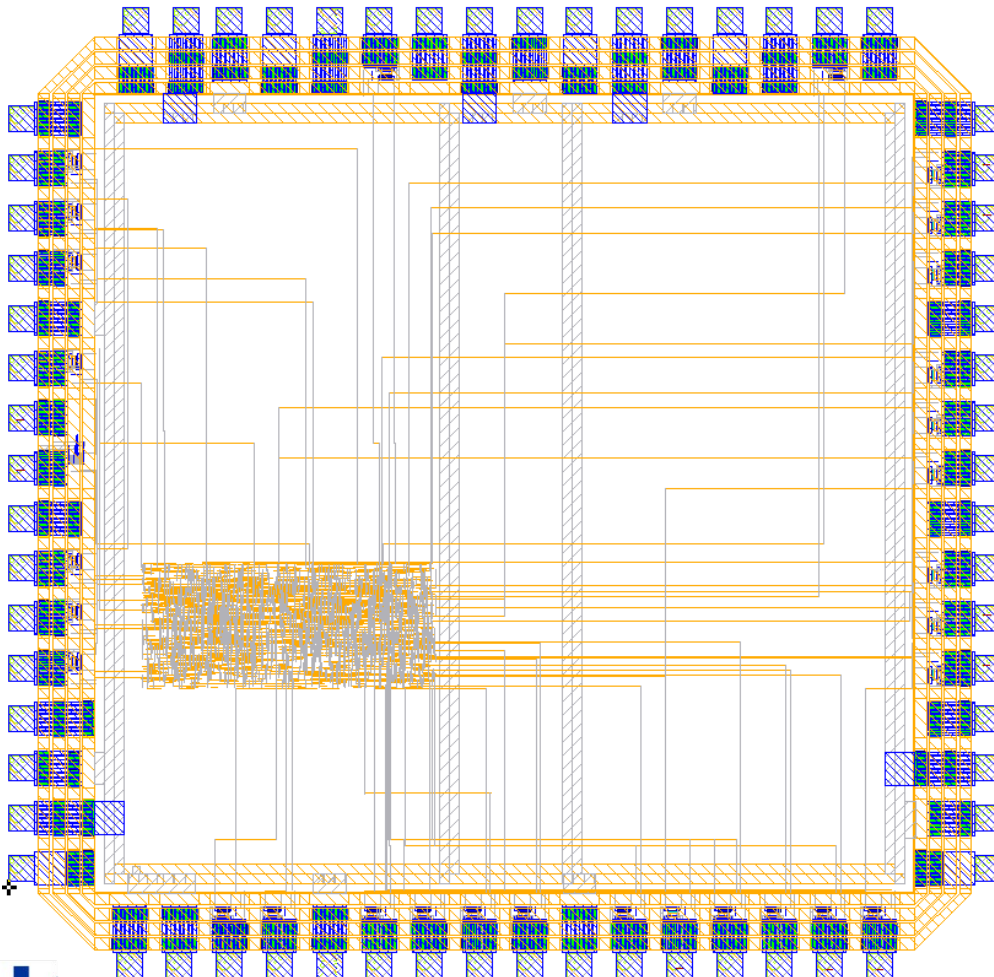


Standard Flip-Flop



DICE Flip-Flop

- EDAC to be incorporated into SRAM
- Radiation Testing
 - Pending support and access to AFRL test facilities



- Silicon in a Phase 1 SBIR
- Design and Layout using 0.5V DG Flexfet cell library and digital design flow developed for picL
- Demonstrates 0.5V DG Standard Cells
- Evaluates SPICE models against silicon results
- Enhances Phase 2 effort

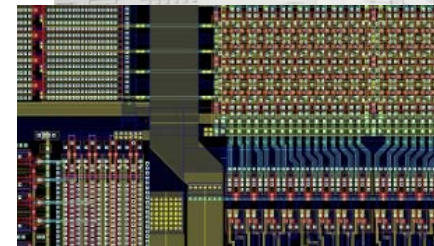
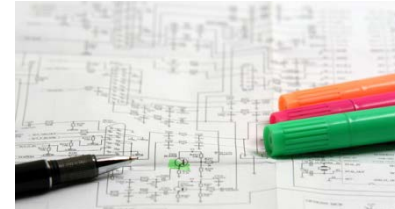
Test Chip Circuits

- 16-bit configurable Timer
- Scan chain with all combinatorial logic gates observable
- Ultra low voltage pads (0.5V)
- Clock oscillator for use with external crystal



In cooperation with the ULP'09 program
AFRL/RVSE

- Phase 1 – Complete
 - Technology evaluation
 - Microprocessor core selection
 - Library preparation and design flow development
 - Performance, power, and radiation tolerance analysis
 - Test circuits in silicon
 - Initial place and route of SPA-1 ASIM RTL
- Phase 2 – Awaiting Contract
 - ASIM ULP SPA-1 Prototype Design Start 2011
 - Detailed device specification
 - RTL design optimization
 - Rad-hard SRAM with compiler
 - Rad-hard ROM with compiler
 - I/O library
 - 1st Silicon ULP SPA-1 Prototype 2012
 - 2nd Silicon ULP SPA-1 Prototype 2013
- Creates Platform and Design Capability for Derivative Products



American Semiconductor Inc.

Thank You

View a video demonstration of ultra-low-power Flexfet at
americansemi.com/Flexfet

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